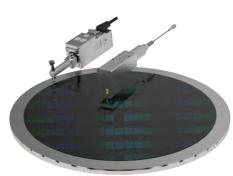


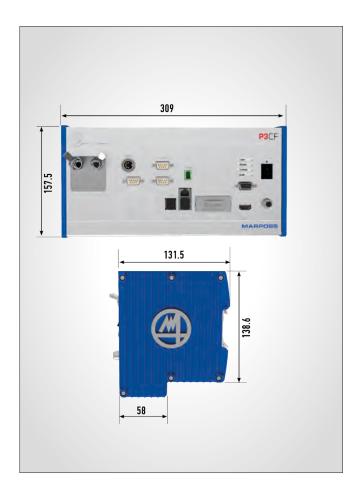
P3 CF

Finishing process of thin and delicate materials (like ceramics, semiconductor wafers, epoxy mold compound for packaging, etc.) requires accurate thickness measurements not always possible using contact probes. Employing confocal technology, P3CF overcomes such limits by carrying out an indirect measurement of thickness as the difference between the distance of the workpiece and the distance of the reference support

Moreover, since the support is typically a less delicate surface which stands a contact measurement, it is also possible to configure the system for a hybrid measurement combining both contact and optical probes.







P3CF UNIT	SPECIFICATION	
MEASURING FREQUENCY	up to 2.000 Hz	
LIGHT SOURCE	LED	
STANDARD MEASURING MODE	Distance	
RESOLUTION	0.25 μm	
ANALOG OUT	2 (0-10Vdc)	
FIELDBUS	Optional	
ENCODER INPUTS	3 digital (TTL/HTL Differential/Single Ended)	
WEIGHT	3.5 Kg	
POWER SUPPLY / CONSUMPTION	24V / 20W	
WORKING TEMPERATURE	5°C - 50°C	
PROTECTION RATING	IP40	

UNIMAR PROBE	Measuring Unit	Values
WORKING RANGE	[µm]	+/- 2000
WEIGHT	[Kg]	0.45
PROTECTION RATING	IP67	
CONFOCAL PROBE	Measuring Unit	Values
MEASURE RANGE	[<i>μ</i> m]	0 - 2000
WORKING DISTANCE	[µm]	2000
SPOT DIAMETER	[<i>μ</i> m]	20
WEIGHT	[Kg]	1.1
PROTECTION RATING	IP68	

For a full list of address locations, please consult the Marposs official website

Edition 04/2023 - Specifications are subject to modifications © Copyright 2023 MARPOSS S.p.A. (Italy) - All rights reserved.

MARPOSS, logo and Marposs product names/signs mentioned or shown herein are registered trademarks or trademarks of Marposs in the United States and other countries. The rights, if any, of third parties on trademarks or registered trademarks mentioned in the present publication are acknowledged to the respective owners.